



# ARFTG 90<sup>th</sup> Microwave Measurement Conference

Boulder, Colorado, USA, November 28<sup>th</sup> – December 1<sup>st</sup>, 2017

[www.arftg.org](http://www.arftg.org)

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## CALL FOR PAPERS

You are invited to submit a paper to the 90<sup>th</sup> ARFTG Microwave Measurement Symposium. We encourage the submission of original papers demonstrating innovative approaches in all aspects of RF Test and Measurement. Contributions exploring all areas of microwave, RF, and mm-wave measurements are welcome. Suggested topics include but are not limited to:

- *Measurements for wireless and guided-wave communication systems*
- *Waveform characterization and noise measurements*
- *Measurements of adaptable, reconfigurable materials and devices (e.g. cognitive radio)*
- *Enabling microwave and mm-wave measurements for the internet of things*
- *RF, Microwave, and mm-wave characterization of devices and material systems*
- *Linear and nonlinear vector network analysis*
- *On-wafer measurement, calibration, and de-embedding techniques*
- *General advances in microwave metrology, measurement and calibration techniques*

## Deadlines

**September 29, 2017** Electronic Abstract/Summary due in PDF format

**November 1, 2017** Publication-ready paper due in PDF format.

Paper acceptance and classification will be communicated by **October 17, 2017**

Instructions for authors are outlined briefly below. More details can be found on the ARFTG web-site: <http://www.arftg.org/index.php/upcoming-conference/author-instructions> Authors are strongly encouraged to use the template on that webpage to prepare both initial summary final paper submissions.

## Instructions for Authors

Contributed papers will be presented as 20-minute talks or in an interactive poster session, and published as part of the ARFTG proceedings in IEEE Xplore.

We request that authors submit a 4-page summary with supporting figures of both experimental setups and measurement results to enable evaluation with regard to the interests of the participants and novelty of the work.

## Student Fellowship Program

To recognize and provide financial assistance to graduate students who show promise and interest in pursuing research related to improvement of radio frequency and microwave measurement techniques. The fellowship is named in memorial of Roger Pollard, in honor of his leadership in Microwave Measurement and Microwave Measurement education. Application deadline: October 1, 2017. [http://www.arftg.org/student\\_fellowship.html](http://www.arftg.org/student_fellowship.html)

## Exhibit & Sponsorship

The 90<sup>th</sup> ARFTG Conference also offers an outstanding exhibition and sponsorship opportunity. Please contact our Exhibits Chair (Joel Dunsmore, [exhibits@arftg.org](mailto:exhibits@arftg.org)) or our Sponsors Chair (Mohamed Sayed, [sponsorship@arftg.org](mailto:sponsorship@arftg.org)) directly for further information.

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